IN THE CLAIMS:

Please amend claims 1, 10 and 11 are as follows.

1. (Currently Amended) A method, comprising:

determining if a memory is functional based on memory BIST data;

selecting a redundant memory section if a portion of the memory is determined to be nonfunctional;

determining if at least the selected redundant memory is functional according to a BIST;

selecting alternate redundant memory sections, if the selected redundant memory section is non-functional, until at least one of the memory is determined to be functional or all redundant memory sections have been selected; and

updating a redundant memory data structure to indicate that the selected redundant memory section is no longer redundant.

2. (Original) The method of claim 1, further comprising storing data indicating the selected redundant memory section.

3. (Original) The method of claim 1, further comprising outputting a pass or fail signal based on the determining if at least the selected redundant memory is functional according to a BIST.

4. (Original) The method of claim 1, wherein the redundant memory section includes a column or row.

5. (Original) The method of claim 1, wherein the redundant memory section includes a bit.

6. (Original) The method of claim 1, wherein the selecting selects a redundant memory section from a redundant memory data structure.

7. (Cancelled)

8. (Original) The method of claim 1, wherein the method is performed during a manufacturing process.

9. (Original) The method of claim 1, wherein the method is performed during power up of an integrated circuit.

10. (Currently Amended) A system, comprising:

means for determining if a memory is functional based on memory BIST data;

means for selecting a redundant memory section if a portion of the memory is determined to be nonfunctional;

means for determining if at least the selected redundant memory is functional according to a BIST;

means for selecting alternate redundant memory sections, if the selected redundant memory section is non-functional, until at least one of the memory is determined to be functional or all redundant memory sections have been selected;; and

means for updating a redundant memory data structure to indicate that the selected redundant memory section is no longer redundant.

11. (Currently Amended) A system, comprising:

a BIST capable of determining if a memory is functional; and

self-adaptive logic, communicatively coupled to the BIST, capable of selecting a redundant memory section if a portion of the memory is determined to be nonfunctional;

wherein the BIST is further capable of determining if at least the selected redundant memory is functional, selecting alternate redundant memory sections, if the selected redundant memory section is non-functional, until at least one of the memory is determined to be functional or all redundant memory sections have been selected and updating a redundant memory data structure to indicate that the selected redundant memory section is no longer redundant.

12. (Original) The system of claim 11, further comprising a register communicatively coupled to the self-adaptive logic and wherein the self-adaptive logic is

further capable of storing data indicating the selected redundant memory section in the register.

13. (Original) The system of claim 11, further comprising a pin and wherein the self-adaptive logic if further capable of outputting a pass or fail signal based on the BIST determination of the functionality of the selected redundant memory.

14. (Original) The system of claim 11, wherein the redundant memory section includes a column or row.

15. (Original) The system of claim 11, wherein the redundant memory section includes a bit.

16. (Original) The system of claim 11, further comprising a redundant memory data structure listing redundant memory sections and wherein the self-adaptive logic selects a redundant memory section from the redundant memory data structure.

17. (Cancelled)

18. (Original) The system of claim 11, wherein the BIST and the self-adaptive logic function during a manufacturing process.

19. (Original) The system of claim 11, wherein the BIST and the self-adaptive logic function during power up of the system.